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United States Patent [19]

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Nightingale et al.

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[54] **PROBING HEAD FOR AN ELECTRICAL TEST PROBE**

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[73] Assignee: **Tektronix, Inc.**, Wilsonville, Oreg.

[**] Term: **14 Years**

[21] Appl. No.: **5,282**

[22] Filed: **Mar. 1, 1993**

[52] U.S. Cl. **D10/78**

[58] Field of Search **324/72.5, 158 P; D10/78**

[56] **References Cited**

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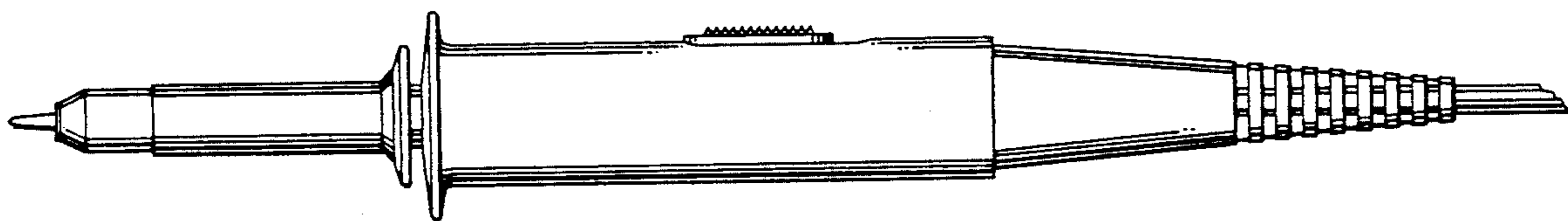
[57] **CLAIM**

The ornamental design for a probing head for an electrical test probe, as shown and described.

DESCRIPTION

FIG. 1 is a left side elevation view of the probing head for an electrical test probe showing our new design; FIG. 2 is a right side elevation view thereof; FIG. 3 is a top plan view thereof; FIG. 4 is a bottom plan view thereof; FIG. 5 is a front elevation view thereof; and, FIG. 6 is a rear elevation view thereof.

The cord member has been broken away indicating an indeterminate length.



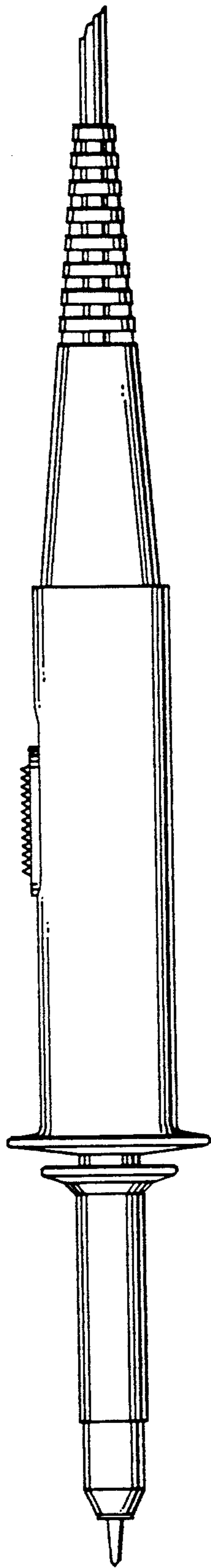


Fig. 1

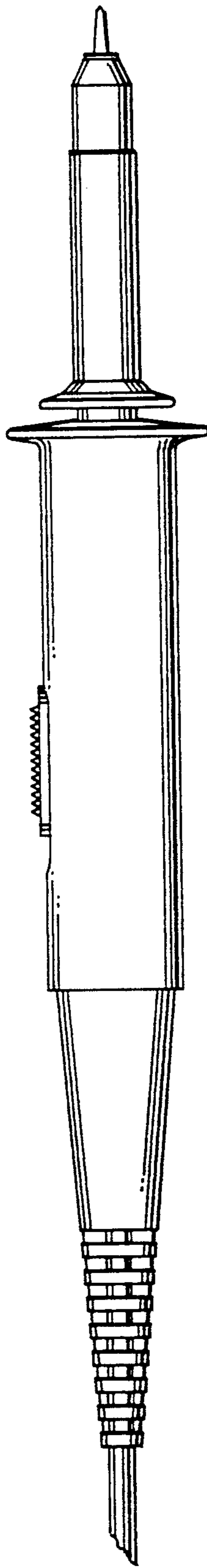


Fig. 2

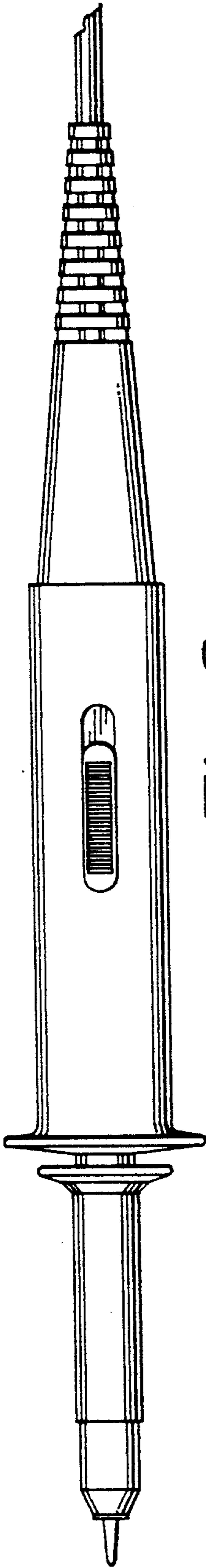


Fig. 3

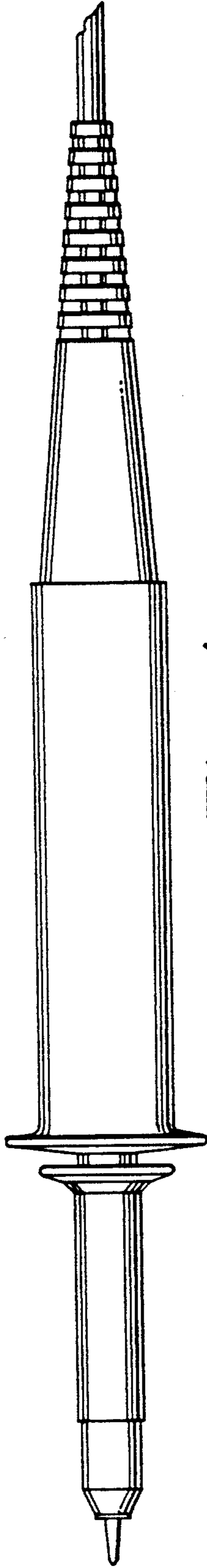


Fig. 4

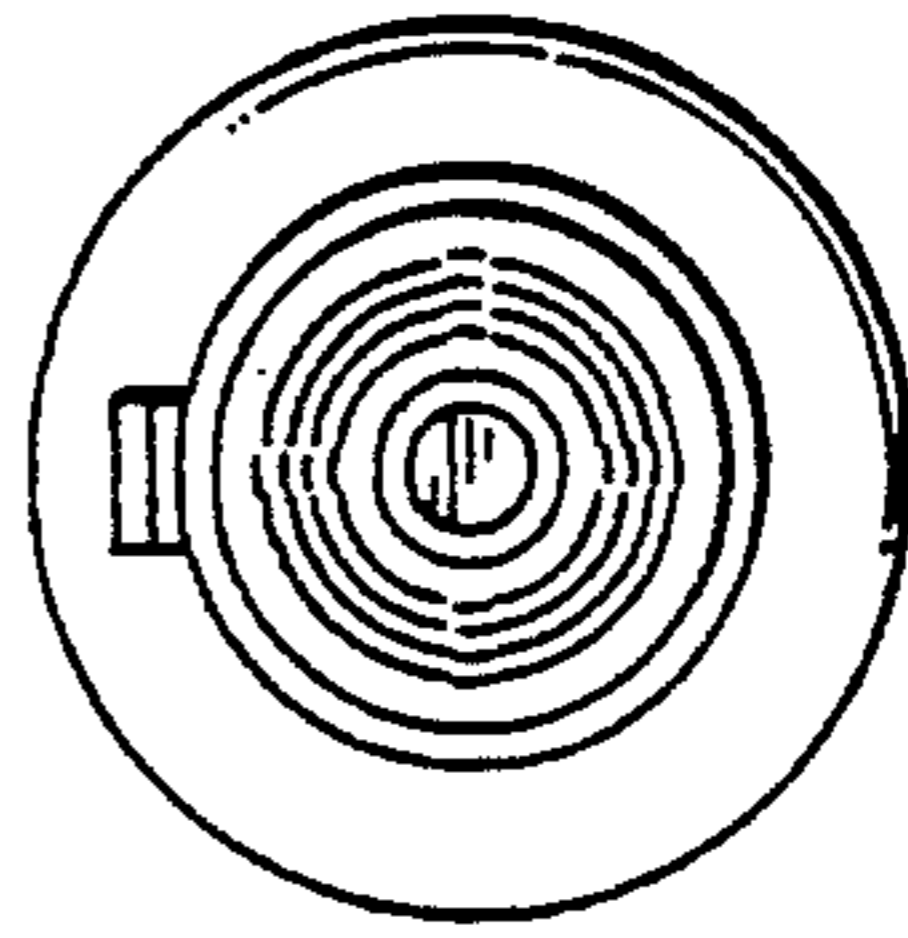


Fig. 6

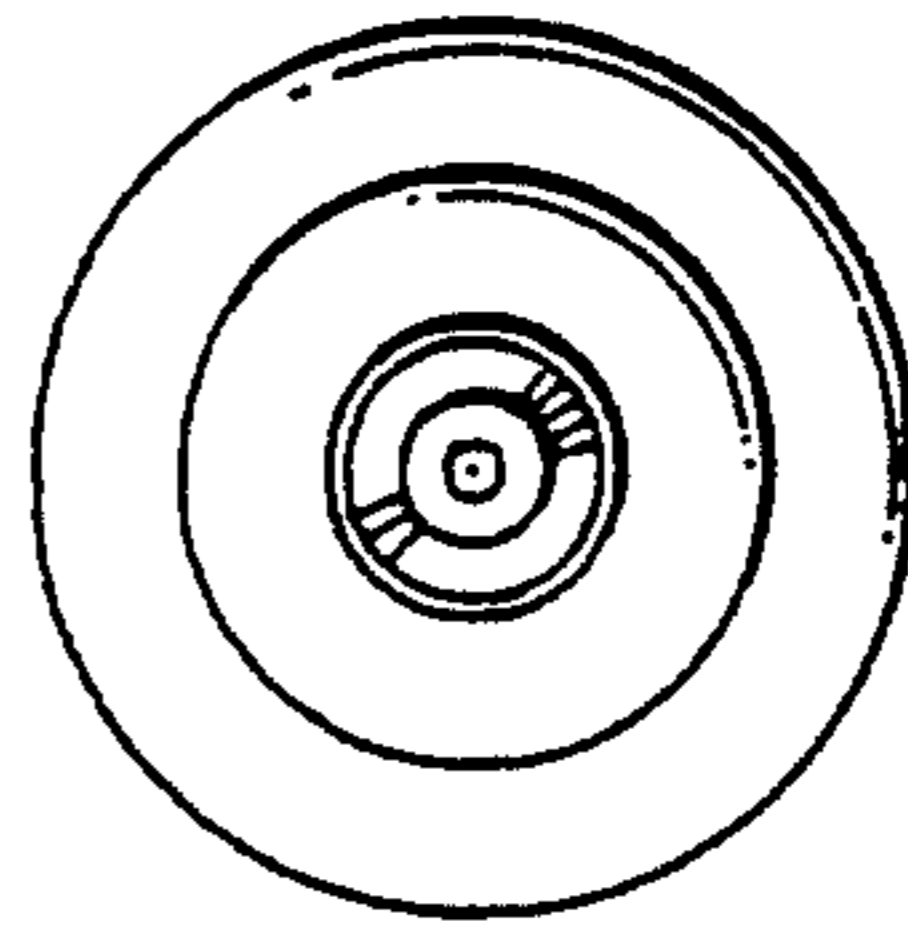


Fig. 5